

What is claimed is:

1 1. An integrated circuit, comprising:
2 one or more memory cells, each memory cell
3 comprising first and second p-channel transistor and first
4 and second n-channel transistors configured as cross-coupled
5 logic inverters between first and second reference voltage
6 levels during a normal mode of operation; and
7 power control circuitry coupled to a source
8 terminal of the first p-channel transistor of each memory
9 cell, for providing to the first p-channel transistors the
10 first reference voltage level during the normal mode of
11 operation, and causing a first voltage less than the first
12 reference voltage level to appear at the source terminal of
13 the first p-channel transistors during a data corruption mode
14 of operation wherein data stored in the one or more memory
15 cells is corrupted.

1 2. The integrated circuit of claim 1, wherein the power
2 control circuitry is coupled to a source terminal of the
3 second p-channel transistor of each memory cell, for
4 providing to the first p-channel transistor the first
5 reference voltage level during the normal mode of operation,
6 and the first voltage during the data corruption mode of
7 operation.

1 3. The integrated circuit of claim 1, wherein the power
2 control circuitry is coupled to a source terminal of at least
3 one of the first and second n-channel transistor, for
4 providing to the at least one of the first and second n-
5 channel transistors the second reference voltage level during
6 the normal mode of operation, and for causing a second
7 voltage greater than the second reference voltage level to
8 appear on the source terminal of at least one of the first
9 and second n-channel transistors during the data corruption
10 mode of operation.

1 4. The integrated circuit of claim 3, wherein the at
2 least one of the first and second n-channel transistor has
3 a drain terminal coupled to a drain terminal of the second
4 p-channel transistor.

1 5. The integrated circuit of claim 3, wherein, during
2 the data corruption mode of operation, the power control
3 circuitry pulses the source terminal of the first p-channel
4 transistor of each memory cell to the first voltage, and
5 pulses the source terminal of the at least one of the first
6 and second n-channel transistors to the second voltage, the
7 pulses partially overlapping.

1 6. The integrated circuit of claim 5, wherein, during
2 the data corruption mode of operation, a leading edge of the
3 pulse corresponding to the first p-channel transistor occurs
4 prior to a leading edge of the pulse corresponding to the at
5 least one of the first and second n-channel transistors.

1 7. The integrated circuit of claim 6, wherein, during
2 the data corruption mode of operation, a trailing edge of the
3 corresponding to the first p-channel transistor occurs prior
4 to a trailing edge of the pulse corresponding to the at least
5 one of the first and second n-channel transistors.

1 8. The integrated circuit of claim 5, wherein the power
2 control circuitry temporarily shorts the source terminal of
3 the first p-channel transistor in each memory cell to the
4 source terminal of the at least one of the first and second
5 n-channel transistors in each memory cell.

1 9. The integrated circuit of claim 8, wherein the power
2 control circuitry comprises at least one first control
3 transistor coupled between the source terminal of the first
4 p-channel transistor of each memory cell to the source
5 terminal of the at least one of the first and second n-
6 channel transistors of each memory cell.

1 10. The integrated circuit of claim 8, wherein the
2 power control circuitry further comprises at least one second
3 control transistor coupled between the first reference
4 voltage level and the source terminal of the first transistor
5 of each memory cell, and at least one third control
6 transistor coupled between the second reference voltage level
7 and the source terminal of the at least one of the first and
8 second n-channel transistors of each memory cell.

1 11. The integrated circuit of claim 1, wherein the
2 first voltage is the second reference voltage level.

1 12. The integrated circuit of claim 1, wherein the
2 first voltage is a voltage resulting from the source terminal
3 of the first p-channel transistor of each memory cell being
4 in an undriven state during the data corruption mode of
5 operation.

1 13. The integrated circuit of claim 1, wherein each
2 memory cell further comprises at least one pass gate
3 transistor having a conduction terminal coupled to at least
4 one bit line and a control terminal coupled to a word line,
5 and the power control circuitry drives the bit lines to a
6 voltage corresponding to a predetermined logic value and
7 drives each word line to a voltage to activate each pass gate
8 transistor during the data corruption mode of operation when
9 the source terminal of the first p-channel transistor of each
10 memory cell is at the first voltage.

1 14. A method of corrupting data values stored in a
2 plurality of memory cells coupled between at least one first
3 node and at least one second node, the method comprising:
4 decoupling the at least one first node from a first
5 reference voltage level and causing a first voltage less than
6 the first reference voltage level to appear on the at least
7 one first node; and
8 following the step of decoupling, driving the at
9 least one first node towards the first reference voltage
10 level.

1 15. The method of claim 14, further comprising driving
2 the at least one second node to a second reference voltage
3 level during the step of driving the at least one first node.

1 16. The method of claim 15, further comprising
2 decoupling, during at least a portion of the time the at
3 least one first node is decoupled from the first reference
4 voltage level and prior to the step of driving the at least
5 one second node, the at least one second node from the second
6 reference voltage level and causing a second voltage greater
7 than the second reference voltage level to appear on the at
8 least one second node.

1 17. The method of claim 16, wherein the step of causing
2 a second voltage comprises driving the at least one second
3 node to the second voltage.

1 18. The method of claim 16, wherein the second voltage
2 is the first reference voltage level.

1 19. The method of claim 16, wherein the step of
2 decoupling the at least one second node occurs after the step
3 of decoupling the at least one first node.

1 20. The method of claim 16, further comprising shorting
2 the at least one first power supply node to the at least one
3 second power supply node following the steps of decoupling
4 the at least one first power supply node and the at least one
5 second power supply node.

1 21. The method of claim 15, wherein the first voltage
2 is the second reference voltage level.

1 22. The method of claim 14, wherein the step of causing
2 a first voltage comprises driving the at least one first
3 power supply node to the first voltage.

1 23. A system, comprising:
2 a processing unit; and
3 one or more memory cells coupled to the processing
4 unit, each memory cell capable of storing one or more data
5 values therein and being coupled to first and second power
6 supply nodes; and
7 power control circuitry, coupled to the one or more
8 memory cells, for placing a first reference voltage on the
9 first power supply node and a second reference voltage on the
10 second power supply node during a normal mode of operation,
11 and causing a first voltage less than the first reference
12 voltage to appear on the first power supply node during a
13 data corruption mode of operation wherein the one or more
14 data values stored in each of the one or more memory cells
15 are corrupted.

1 24. The system of claim 23, wherein the first voltage
2 is the second reference voltage.

1 25. The system of claim 23, wherein each memory cell
2 comprises first and second p-channel transistors and first
3 and second n-channel transistors configured as a logic
4 inverter during the normal mode of operation, the first p-
5 channel transistor having a source terminal coupled to the
6 first power supply node.

1 26. The system of claim 25, wherein a source terminal
2 of the second p-channel transistor of each memory cell is
3 coupled to a third power supply node, the third power supply
4 node having the first reference voltage during the normal and
5 data corruption modes of operation.

1 27. The system of claim 26, wherein the power control
2 circuitry comprises a logic inverter having an output coupled
3 to the first power supply node.

1 28. The system of claim 26, wherein the power control
2 circuitry comprises a transistor coupled between a system
3 power line and the first power supply node.

1 29. The system of claim 25, wherein a source terminal
2 of the second p-channel transistor of each memory cell is
3 coupled to the first power supply node.

1 30. The system of claim 25, wherein a source terminal
2 of the second n-channel transistor of each memory cell is
3 coupled to the second power supply node, and a source
4 terminal of the first n-channel transistor of each memory
5 cell is coupled to a fourth power supply node, the fourth
6 power supply node having the second reference voltage during
7 the normal and data corruption modes of operation.

1 31. The system of claim 23, wherein the power control
2 circuitry places the second reference voltage on the second
3 power supply node during the normal mode of operation and
4 causes a second voltage greater than the second reference
5 voltage to appear on the second power supply node during the
6 data corruption mode of operation.

1 32. The system of claim 31, wherein the second voltage
2 is the first reference voltage.

1 33. The system of claim 31, wherein the power control
2 circuitry comprises a first transistor coupled between the
3 first power supply node and the second power supply node, the
4 transistor being activated during a portion of the data
5 corruption mode of operation and deactivated during the
6 normal mode of operation.

1 34. The system of claim 33, wherein the power control
2 circuitry comprises a second transistor coupled between the
3 first power supply node and the second reference voltage, and
4 a third transistor coupled between the second power supply
5 node and the first reference voltage, the second and third
6 transistors being activated during the data corruption mode
7 of operation and deactivated during the normal mode of
8 operation.

1 35. The system of claim 34, wherein during the data
2 corruption mode of operation, the first transistor is
3 activated prior to the second and third transistors being
4 activated.

1 36. The system of claim 31, wherein the power control
2 circuitry comprises a first transistor coupled between a
3 first external voltage supply line and the first power supply
4 node, and a second transistor coupled between a second
5 external voltage supply line and the second power supply
6 node, the first and second transistors being activated during
7 the normal mode of operation and deactivated during at least
8 a portion of the data corruption mode of operation.